SCOPE: MICROPROCESSOR SUPERVISORY CIRCUITS

Device Type	Generic Number
01	MAX690(x)/883B
02	MAX691(x)/883B
03	MAX692(x)/883B
04	MAX693(x)/883B
05	MAX694(x)/883B
06	MAX695(x)/883B

Case Outline(s). The case outlines shall be designated in Mil-Std-1835 and as follows:

Outline Letter MAXIM	Outline Letter SMD	Mil-Std-1835	Case Outline	Package Code
JA	P	GDIP1-T08 or CDIP2-T08	8 LEAD CERDIP	J08
JE	E	GDIP1-T16 or CDIP2-T16	16 LEAD CERDIP	J16
FB	X	CDFP3-F10	10 LEAD Flatpack	F10
LP	2	CQCC1-N20	20 Pin Leadless Chip	L20

Absolute Maximum Ratings

Terminal Voltage (with respect to GND)
- V_{CC} ..... -0.3V to +6.0V
- V_{BATT} ..... -0.3V to+6.0V
- All other Inputs 1/ ..... -0.3V to (V_{OUT}+0.5V)

Input Current
- V_{CC} 200mA
- V_{BATT} 50mA
- GND 20mA

Output Current
- V_{OUT} ..... Short-circuit protected
- All other outputs 20mA

Rate of Rise, V_{CC}, V_{BATT} 100V/µs

Lead Temperature (soldering, 10 seconds) ..... +300°C
Storage Temperature ..... -65°C to +160°C
Continuous Power Dissipation ..... T_A=+70°C
- 8 lead CERDIP(derate 8.0mW/°C above +70°C) 640mW
- 16 lead CERDIP(derate 10.0mW/°C above +70°C) 800mW
- 10 lead Flatpack(derate 5.3mW/°C above +70°C) 421mW
- 20 lead LCC(derate 9.1mW/°C above +70°C) 727mW

Junction Temperature T_J ..... +150°C

Thermal Resistance, Junction to Case, ΘJC:
- Case Outline 8 lead CERDIP..... 55°C/W
- Case Outline 16 lead CERDIP..... 50°C/W
- Case Outline 10 lead Flatpack ..... 85°C/W
- Case Outline 20 leadless Chip carrier ..... 20°C/W

Thermal Resistance, Junction to Ambient, ΘJA:
- Case Outline 8 lead CERDIP..... 125°C/W
- Case Outline 16 lead CERDIP..... 100°C/W
- Case Outline 10 lead Flatpack ..... 190°C/W
- Case Outline 20 leadless Chip carrier ..... 110°C/W

NOTE 1: The input voltage limits on PFI and WDI may be exceeded if the input current is less than 10mA.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Ambient Operating Range (T_A) ..... -55°C to +125°C
Supply Voltage Range (V_{CC}) DASH 03 & 04 ..... +4.5V to +5.5V
Supply Voltage Range (V_{CC}) DASH 01, 02, 05, 06 ..... +4.75V to +5.5V

TABLE 1. ELECTRICAL TESTS:

TEST	Symbol	CONDITIONS -55 °C ≤T_A≤+125°C 2/ Unless otherwise specified	Group A Subgroup	Device type	Limits Min	Limits Max	Units
BATTERY-BACKUP SWITCHING							
Operating Voltage Range	V_{CC}		1,2,3	01,02, 05,06	4.75	5.5	V
				03,04	4.5	5.5	
Operating Voltage Range	V_{BATT}		1,2,3	01,02, 05,06	2.0	4.25	V
				03,04	2.0	4.0	
Output Voltage	V_{OUT}	I_{OUT}=1mA I_{OUT}=50mA	1,2,3	All	V_{CC}-0.3 V_{CC}-0.5		V
Output Voltage-Battery-Backup Mode	BATT OUT	I_{OUT}=250µA, V_{CC}<V_{BATT}-0.2V	1,2,3	All	VBATT-0.1		V
Supply Current (Excludes I_{OUT})	I_{CC}	I_{OUT}=1mA	1 2,3	All		5 7	mA
		I_{OUT}=50mA	1 2,3			10 15	
Supply Current in Battery-Backup Mode	I_{BATT}	V_{CC}=0V, V_{BATT}=2.8V	1 2,3	All		1 10	µA
Battery Standby Current	BATT SBI	5.5V>V_{CC}>V_{BATT}+1V +=Discharge, -=Charge	1 2,3	All	-0.10 -1.00	+0.02 +0.02	µA
Battery-Switchover, Threshold, V_{CC} to V_{BATT}	BATT SW_{TH}	Power-Up or Power-Down	1,2,3	All	-200	+200	mV
BATT ON Output Voltage	BATT ON_{OUT}	I_{SINK}=3.2mA	1,2,3	02,04,06		0.4	V
BATT ON Output Short-Circuit Current	BATT ON_{IOS}	BATT ON = V_{OUT}	1,2,3	02,04,06		60	mA
		BATT ON =0V Source Current			0.1	25	µA
RESET AND WATCHDOG TIMING							
Reset Voltage Threshold	R_{TH}		1,2,3	01,02, 05,06	4.5	4.75	V
				03,04	4.25	4.5	
Reset Threshold Hysteresis	RT_{HH}		1,2,3	All		250	mV
Reset Timeout Delay	R_{DEL}	OSC SEL High, V_{CC}=5V	9 10,11	01,02 03,04	35 31	70 78	ms
			9 10,11	05,06	140 126	280 310	

TEST	Symbol	CONDITIONS -55 °C ≤T_A≤+125°C 2/ Unless otherwise specified	Group A Subgroup	Device type	Limits Min	Limits Max	Units
Watchdog Timeout Period, Internal Oscillator	WD_{INT}	Long Period, V_{CC}=5V	9 10,11	All	1.00 0.90	2.25 2.42	sec
		Short Period, V_{CC}=5V	9 10,11		70 62	140 154	ms
Watchdog Timeout Period, External Clock	WD_{EXT}	Long Period	9 10,11	02,04,06	3840	4097	Clock Cycles
		Short Period	9 10,11	02,04,06	768	1025	
Minimum WDI Input Pulse Width	WDI_{PW}	V_{IL}=0.4V, V_{IH}=V_{CC}(0.8)	9 10,11	All	200 300		ns
$\overline{\text{RESET}}$ Output Voltage High	$\overline{R}_{VOH}$	I_{SOURCE}=1µA, V_{CC}=5V	1,2,3	All	3.5		V
$\overline{\text{RESET}}$ Output Voltage Low	$\overline{R}_{VOL}$	I_{SINK}=1.6mA, V_{CC}=4.25V	1	All		0.4	V
		I_{SINK}=800µA, V_{CC}=4.25V	2,3			0.4	
$\overline{\text{LOWLINE}}$ Output Voltage High	$\overline{LL}_{VOH}$	I_{SOURCE}=1µA, V_{CC}=5V	1,2,3	02,04,06	3.5		V
$\overline{\text{LOWLINE}}$ Output Voltage Low	$\overline{LL}_{VOL}$	I_{SINK}=1.6mA, V_{CC}=4.25V	1	02,04,06		0.4	V
		I_{SINK}=800µA, V_{CC}=4.25V	2,3			0.4	
$\overline{\text{WDO}}$ Output Voltage High	$\overline{WDO}_{VOH}$	I_{SOURCE}=1µA, V_{CC}=5V	1,2,3	All	3.5		V
$\overline{\text{WDO}}$ Output Voltage Low	$\overline{WDO}_{VOL}$	I_{SINK}=1.6mA, V_{CC}=4.25V	1	02,04,06		0.4	V
		I_{SINK}=800µA, V_{CC}=4.25V	2,3			0.4	
Reset Output Voltage High	R_{VOH}	I_{SOURCE}=1µA, V_{CC}=5V	1,2,3	02,04,06	3.5		V
Reset Output Voltage Low	R_{VOL}	I_{SINK}=1.6mA	1	02,04,06		0.4	V
		I_{SINK}=800µA	2,3			0.4	
Output Short-Circuit Current	I_{OS}	$\overline{\text{RESET}}$=0V	1,2,3	All	1	25	µA
		$\overline{\text{RESET}}$, $\overline{\text{RESET}}$, $\overline{\text{WDO}}$, $\overline{\text{LL}}$		02,04,06	1	25	
WDI Input Threshold Logic Low	WDI_{VIL}	V_{CC}=5V NOTE 3	1 2,3	All		0.8 0.4	V
WDI Input Threshold Logic High	WDI_{VIH}	V_{CC}=5V NOTE 3	1 2,3	All	3.5 4.0		V
WDI Input Current	WDI_{IN}	WDI=V_{OUT}	1 2,3	All		50 80	µA
		WDI=0V	1 2,3		-50 -80		

TEST	Symbol	CONDITIONS -55 °C ≤T_A≤+125°C 2/ Unless otherwise specified	Group A Subgroup	Device type	Limits Min	Limits Max	Units
POWER-FAIL DETECTOR							
PFI Input Threshold	PFI_{VTH}	V_{CC}=5V	1,2,3	All	1.2	1.4	V
PFI Input Current	$PFII_{IN}$		1,2,3	All	-25	25	nA
$\overline{PFO}$ Output Voltage High	$\overline{PFO}_{VOH}$	I_{SOURCE}=1µA, V_{CC}=5V	1,2,3	All	3.5		V
$\overline{PFO}$ Output Voltage Low	$\overline{PFO}_{VOL}$	I_{SINK}=3.2mA I_{SINK}=1.6mA	1 2,3	All		0.4 0.4	V
$\overline{PFO}$ Short-Circuit Source Current	$\overline{PFO}_{IOS}$	PFI=V_{IH}, $\overline{PFO}$=0V	1,2,3	All	1.0	25	µA
CHIP-ENABLE GATING							
$\overline{CE}$ IN Thresholds Logic Low	$\overline{CE}V_{IL}$		1 2,3	02,04,06		0.8 0.4	V
$\overline{CE}$ IN Thresholds Logic High	$\overline{CE}V_{IH}$		1 2,3	02,04,06	3.0 4.0		V
$\overline{CE}$ IN Pull-Up Current	$\overline{CE}$ IN_{PI}		1,2,3	02,04,06	1.0	25	µA
$\overline{CE}$ OUT Output Voltage High	$\overline{CE}_{VOH}$	I_{SOURCE}=3.0mA, V_{CC}=4.75V I_{SOURCE}=1µA, V_{CC}=0V	1,2,3	02,04,06	V_{OUT}-1.5 V_{OUT}-0.05		V
$\overline{CE}$ Output Voltage Low	$\overline{CE}_{VOL}$	I_{SINK}=3.2mA I_{SINK}=1.6mA	1 2,3	02,04,06		0.4 0.4	V
$\overline{CE}$ Propagation Delay	t_{PDCE}	V_{CC}=5V	9 10,11	02,04,06		200 300	ns
OSCILLATOR							
OSC IN Input Current Pull-Up	$OSCI_{IN}$		1,2,3	02,04,06		25	µA
OSC SEL Input Pull-Up Current	OSC SEL_{IN}		1,2,3	02,04,06	1	25	µA
OSC IN Frequency Range	OSC INfrq	OSC SEL=0V	9,10,11	02,04,06	0	250	kHz
OSC IN Frequency with External Capacitor	OSC_{IN}	OSC SEL=0V, COSC=47pF NOTE 4	9	02,04,06	4		kHz

NOTE 2: V_{CC}=full operating range, V_{BATT}=+2.8V.
NOTE 3: WDI is guaranteed to be in the mid-level (inactive) state if WDI is floating and V_{CC} is in the operating range. WDI is internally biased to 38% of V_{CC} with an impedance of approximately 125kΩ
NOTE 4: Typical for design purposes only but not tested. Guaranteed for SMD 5962-90711 and 5962-90712.

	Package	ORDERING INFORMATION:	SMD NUMBER
01	8 pin CERDIP	MAX690MJA/883B	5962-9071201MPA
01	10 pin Flatpack	MAX690MFB/883B	5962-9071201MXC
01	20 pin LCC	MAX690MLP/883B	5962-9071201M2C
02	8 pin CERDIP	MAX691MJA/883B	5962-9071101MPA
02	20 pin LCC	MAX691MLP/883B	5962-9071101M2C
03	8 pin CERDIP	MAX692MJA/883B	5962-9071202MPA
03	10 pin Flatpack	MAX692MFB/883B	5962-9071202MXC
03	20 pin LCC	MAX692MLP/883B	5962-9071202M2C
04	8 pin CERDIP	MAX693MJA/883B	5962-9071102MPA
04	20 pin LCC	MAX693MLP/883B	5962-9071102M2C
05	8 pin CERDIP	MAX694MJA/883B	5962-9071203MPA
05	10 pin Flatpack	MAX694MFB/883B	5962-9071203MXC
05	20 pin LCC	MAX694MLP/883B	5962-9071203M2C
06	8 pin CERDIP	MAX695MJA/883B	5962-9071103MPA

TERMINAL CONNECTIONS:

	MAX690/692/694	MAX690/692/694	MAX690/692/694	MAX691/693/695	MAX691/693
	J8	F10	L20	J16	L20
1	V_{OUT}	V_{OUT}	NC	V_{BATT}	NC
2	V_{CC}	V_{CC}	V_{BATT}	V_{OUT}	V_{BATT}
3	GND	GND	V_{OUT}	V_{CC}	V_{OUT}
4	PFI	NC	V_{CC}	GND	V_{CC}
5	$\overline{PFO}$	PFI	GND	BATT ON	GND
6	WDI	$\overline{PFO}$	NC	$\overline{LOWLINE}$	NC
7	$\overline{RESET}$	WDI	NC	OSC IN	BATT ON
8	V_{BATT}	NC	NC	OSC SEL	$\overline{LOWLINE}$
9		$\overline{RESET}$	NC	PFI	OSC IN
10		V_{BATT}	NC	$\overline{PFO}$	OSC SEL
11			NC	WDI	NC
12			PFI	$\overline{CE}$ OUT	PFI
13			$\overline{PFO}$	$\overline{CE}$ IN	$\overline{PFO}$
14			WDI	$\overline{WDO}$	WDI
15			NC	$\overline{RESET}$	$\overline{CE}$ OUT
16			NC	RESET	NC
17			NC		$\overline{CE}$ IN
18			NC		$\overline{WDO}$
19			$\overline{RESET}$		$\overline{RESET}$
20			NC		RESET

QUALITY ASSURANCE

Sampling and inspection procedures shall be in accordance with MIL-Prf-38535, Appendix A as specified in Mil-Std-883.

Screening shall be in accordance with Method 5004 of Mil-Std-883. Burn-in test Method 1015:

1. Test Condition, A, B, C, or D.
2. TA = +125°C minimum.
3. Interim and final electrical test requirements shall be specified in Table 2.

Quality conformance inspection shall be in accordance with Method 5005 of Mil-Std-883, including Groups A, B, C, and D inspection.

Group A inspection:

1. Tests as specified in Table 2.
2. Selected subgroups in Table 1, Method 5005 of Mil-Std-883 shall be omitted.

Group C and D inspections:

a. End-point electrical parameters shall be specified in Table 1.
b. Steady-state life test, Method 1005 of Mil-Std-883:
   1. Test condition A, B, C, D.
   2. TA = +125°C, minimum.
   3. Test duration, 1000 hours, except as permitted by Method 1005 of Mil-Std-883.

TABLE 2. ELECTRICAL TEST REQUIREMENTS

Mil-Std-883 Test Requirements	Subgroups per Method 5005, Table 1
Interim Electric Parameters Method 5004	1
Final Electrical Parameters Method 5005	1*, 2, 3, 9, 10, 11
Group A Test Requirements Method 5005	1, 2, 3, 9, 10, 11
Group C and D End-Point Electrical Parameters Method 5005	1

* PDA applies to Subgroup 1 only.

Компания «ЭлектроПласт» предлагает заключение долгосрочных отношений при поставках импортных электронных компонентов на взаимовыгодных условиях!

Наши преимущества:

- Оперативные поставки широкого спектра электронных компонентов отечественного и импортного производства напрямую от производителей и с крупнейших мировых складов;
- Поставка более 17-ти миллионов наименований электронных компонентов;
- Поставка сложных, дефицитных, либо снятых с производства позиций;
- Оперативные сроки поставки под заказ (от 5 рабочих дней);
- Экспресс доставка в любую точку России;
- Техническая поддержка проекта, помощь в подборе аналогов, поставка прототипов;
- Система менеджмента качества сертифицирована по Международному стандарту ISO 9001;
- Лицензия ФСБ на осуществление работ с использованием сведений, составляющих государственную тайну;
- Поставка специализированных компонентов (Xilinx, Altera, Analog Devices, Intersil, Interpoint, Microsemi, Aeroflex, Peregrine, Syfer, Eurofarad, Texas Instrument, Miteq, Cobham, E2V, MA-COM, Hittite, Mini-Circuits,General Dynamics и др.);

Помимо этого, одним из направлений компании «ЭлектроПласт» является направление «Источники питания». Мы предлагаем Вам помощь Конструкторского отдела:

- Подбор оптимального решения, техническое обоснование при выборе компонента;
- Подбор аналогов;
- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.

Как с нами связаться

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